

Robust Design for the Mechanical Reliability of a 3-D Stacked Module Package

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Abstract

This paper proposes a method for assessing the mechanical reliability assessments and design optimization of a stacked module package (‘SIP). Two geometrical parameters—the flip-chip chip thickness and the substrate thickness, and three material parameters—the polyimide option, the underlayer material, and the bump material, are used to perform parametric studies and factorial design. The three-dimensional finite element analysis (FEA) consists of global and local models using chip sub-modeling technique. The two-stage modeling approach is capable of determining the interfacial stresses, bump stress, and low-k stress. For interfacial stresses, chip shear stress (normal and is consistent with the observation from field data/or underfill delamination. In addition to the interfacial stresses, the bump stress and low-k stress are bonded together to form a multi-objective function enabling design optimization. The desirability of each sub-objective is set to be the minimization. Therefore the best parametric combination can be obtained in order to enhance the IP, mechanical reliability through 2-3 factorial designs.

Keyword : Mechanical reliability, stacked module package, finite element analysis, factorial design.